

**JPL**

*MAX*

## A SPACE STATION COMPUTER OPTION

**D.B. Smith  
R.D. Rasmussen**

**N87-29146**

*P-12*



## GENERAL PURPOSE SPACE COMPUTING

- Typified by most
  - engineering subsystems
  - payloads
  - other "intelligent" devices
- Specifically excludes
  - top end, special-purpose signal processors
  - low end, in-circuit  $\mu$ -processor applications

## **CHARACTERIZED BY**

- **Embedded, real-time applications**
- **Both synchronous, cyclic operation and asynchronous, event driven operation**
- **Both computationally intensive (e.g. signal processing, guidance) and data intensive (e.g. command and telemetry) processing**
- **Wide range of throughput and memory requirements**
- **Range of fault tolerance requirements from none to full, uninterruptable operation through faults or damage**
- **Maintainability, including capability for on-line substitution in critical systems**

***MAX* HARDWARE FEATURES**

- General purpose computer module
  - Small, light weight, & low power
  - Radiation hard & single event upset immune
  - ≈ 1 Million Whetstone equivalent instructions per second (floating point)
  - 256 Kbytes (expandable) memory
  - High speed communication ports & memory mapped I/O
  - Global semaphore capability without shared memory
- Special features support
  - Multi-computer concurrency
  - Software implemented fault tolerance
  - Spatial distribution for damage tolerance

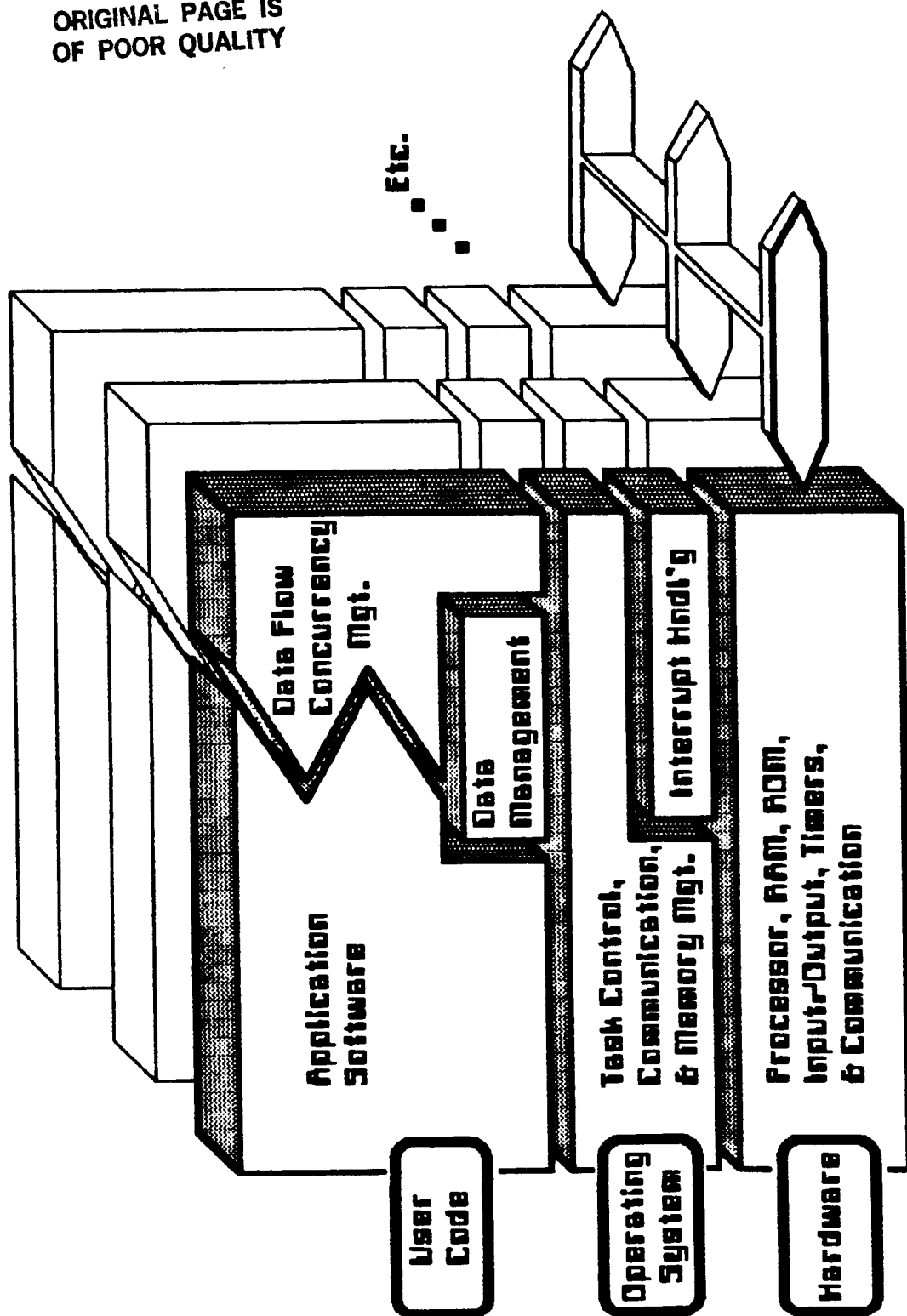
## ***MAX* SOFTWARE FEATURES**

- Conventional programming and test environments
- Layered software design supporting
  - high level languages
  - real time, multi-tasking & task migration
  - packet communication
  - data management
  - concurrency
  - fault tolerance
- Optional low resolution data-flow concurrency support

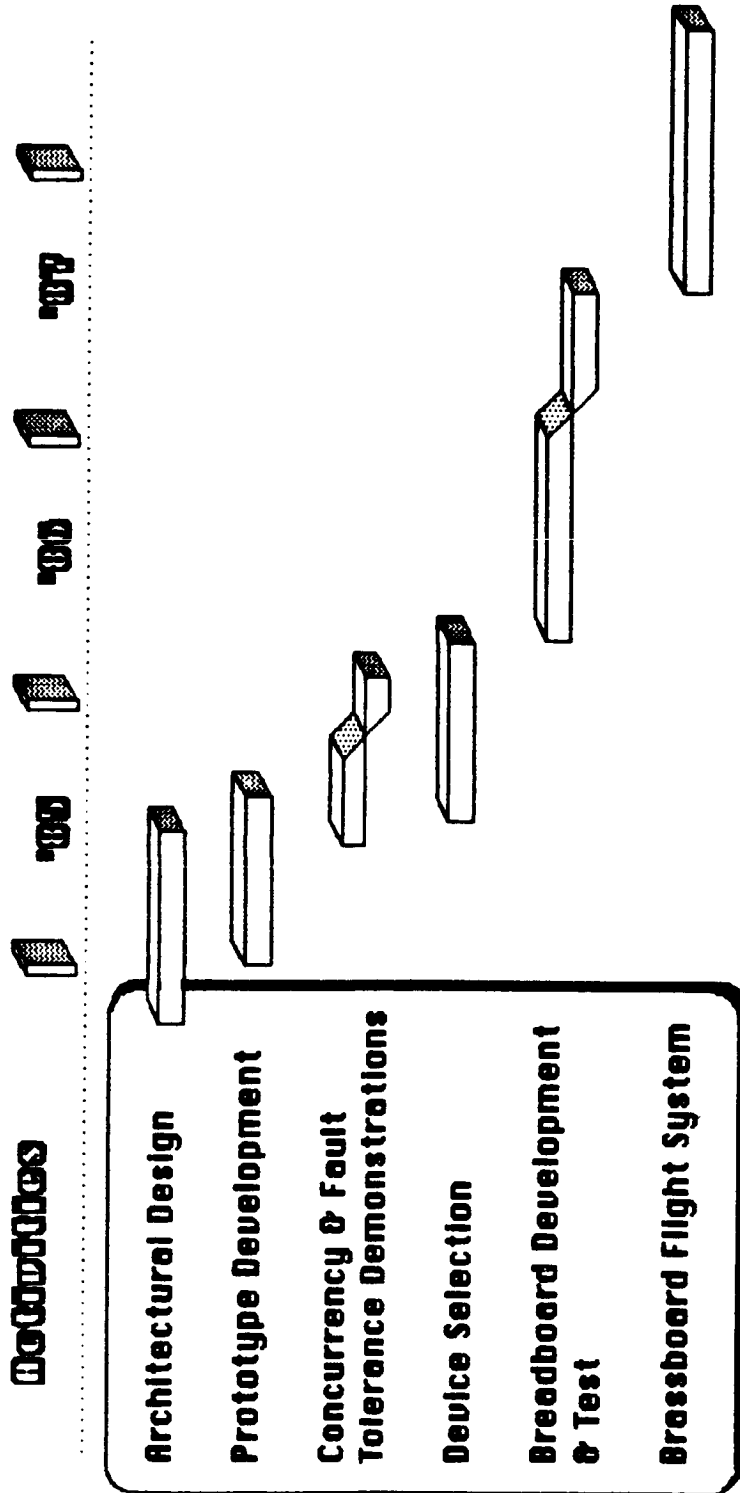
CLASSIFIED  
EXCLUDED FROM AUTOMATIC  
DOWNGRADING AND  
DECLASSIFICATION

# MAX LAYERED ARCHITECTURE

ORIGINAL PAGE IS  
OF POOR QUALITY



# *WAX* DEVELOPMENT PLAN



## IMPLEMENTATION OPTIONS

- Low power bipolar devices are susceptible to single event upset
- Preferred device technology is CMOS
  - High density CMOS is fast, but low power
  - Can be made single event upset immune
- Existing CMOS part sets include
  - Epic bit-slice family & related parts
  - 2900 family bit-slice component emulations
  - Custom standard cell and gate array components
  - 8085, 80C86 and 1802  $\mu$ -processors (& selected peripheral parts)
  - Memory components
- Comparable VHASIC components in development



## PROMISING NEW ARRIVAL

- 2 micron (10-15 MHz) CMOS emulation of National Series 32000™ and supporting devices by Sandia National Laboratories
  - 32032 and 32016  $\mu$ -processors
  - 32081 Floating Point Unit
  - 32201 Timing Control Unit
  - 32202 Interrupt Control Unit (plus timers & I/O)
  - 8Kx8 static RAM, 32Kx8 ROM, 32Kx8 EEPROM, & non-volatile RAM
  - 1K (and 2.5K - 10K ?) gate array
  - Standard cells (up to 30,000 transistors per chip)
  - Miscellaneous glue chips (buffer, latch, decoder, byte I/O,...)
  - Bus arbiter & DMA controller under consideration
- Replacement compatible with commercial versions

## ADVANTAGES

- Prototyping can begin now with commercial parts
- Throughput comparable to VAX-11/750 ( $\approx 1$  MIPS)
- Modern architecture explicitly and efficiently supporting
  - modular programming
  - complex data structures
  - structured language control flow, etc...

Result » lower cost, more compact, more reliable code

- Small chip count and small physical size
- Clean support for custom slave processors
- Wide range of commercially available support tools
- Potential direct path to subsequent VHSIC level integration (NSC is a VHSIC phase I subcontractor to WEC)

## **RADIATION HARDNESS**

- Total dose hardness of  $1 \times 10^6$  Rads (Si)
- No upset to  $1 \times 10^9$  Rads (Si) /sec
- No upset from 140 MeV Krypton, any angle

**SANDIA DEVELOPMENT PLAN**

- NSC enthusiastic and involved in program (contract not yet signed as of March 85)
- Engineering samples of 32016 and all other components (except 32032) available by fourth quarter of 1988
- 32032 available by second quarter 1989
- Six months from engineering samples to production quantities
- JPL considering test & qualification of commercial parts (both NSC & second source TI) for acceptability in low dose environments